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	Application No.	Applicant(s)
Notice of Allowability	10/722,752	NAKAO ET AL.
	Examiner	Art Unit
	John P. Trimmings	2138
The MAILING DATE of this communication appe All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this apport or other appropriate communication GHTS. This application is subject to	plication. If not included will be mailed in due course. THIS
1. \boxtimes This communication is responsive to <u>amendment dated 6/2</u>	<u>29/2006</u> .	
2. A The allowed claim(s) is/are 1-8,10-15, renumbered as 1-14	<u>.</u>	
3. Acknowledgment is made of a claim for foreign priority una a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE" on the delow. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 4. A SUBSTITUTE OATH OR DECLARATION must be submit INFORMAL PATENT APPLICATION (PTO-152) which give 5. CORRECTED DRAWINGS (as "replacement sheets") must (a) Including changes required by the Netice of Draffspace.	been received. been received in Application No cuments have been received in this of this communication to file a reply ENT of this application. itted. Note the attached EXAMINER as reason(s) why the oath or declara	national stage application from the complying with the requirements 'S AMENDMENT or NOTICE OF tion is deficient.
 (a) ☐ including changes required by the Notice of Draftspers 1) ☐ hereto or 2) ☐ to Paper No./Mail Date (b) ☐ including changes required by the attached Examiner's 		,
Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR 1.		
each sheet. Replacement sheet(s) should be labeled as such in the first of the sheet as such in the first of the sheet and sheet as such in the first of the sheet as such in the first of the sheet as such in the first of the sheet as such in the sheet as such in the first of the sheet as such in the first of the sheet as such in the sheet as s	sit of BIOLOGICAL MATERIAL r	nust be submitted. Note the
Attachment(s) 1. ☐ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date	6. ☐ Interview Summary Paper No./Mail Dat 8), 7. ☐ Examiner's Amendr	te

OR to enta, n/ 7/25/06

Application No. 10/722,752 Amendment dated June 29, 2006 Reply to Office Action of April 3, 2006 Docket No.: 967_038

AMENDMENTS TO THE DRAWINGS

The attached sheet(s) of drawings includes changes to Fig. 8.

Attachment:

Replacement sheet

JUN 2 9 2006

Inventor: Toshinobu Nakao et al.
10/722.752 Filed: Nov. 26, 2003

Serial No.: 10/722,752 Art Unit: 2138 Art Unit: 2138 Atty. Docket No.: 967_038
For: Scan Test Control Method And Scan Test Circuit
REPLACEMENT SHEET

START

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A TEST CLOCK, A NORMAL CLOCK, AND A SCAN SELECTION EXTERNAL SIGNAL ARE INPUTTED TO A SCAN TEST CIRCUIT HAVING A SCAN CHAIN! OF n PIECES OF SCAN STORAGE ELEMENTS FROM EXTERNAL INPUT TERMINAL.

A SCAN CONTROL CIRCUIT CHANGES A SCAN CLOCK OF THE n PIECES OF SCAN STORAGE ELEMENTS TO A TEST CLOCK.

THE SCAN CONTROL CIRCUIT RECEIVES THE SCAN SELECTION EXTERNAL SIGNAL, GENERATES A SCAN SELECTION INTERNAL SIGNAL, AND CHANGES THE N PIECES OF SCAN STORAGE ELEMENTS INTO THE SCAN MODE.

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803 DOES THE YES (N-1)th SCAN STORAGE ELEMENT STORE SCAN-IN DATA ?

NO

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THE SCAN CONTROL CIRCUIT RECEIVES THE SCAN SELECTION EXTERNAL SIGNAL, GENERATES A SCAN SELECTION INTERNAL SIGNAL, AND CHANGES THE n PIECES OF SCAN STORAGE ELEMENTS INTO THE SCAN MODE.

ALTHOUGH THE SCAN SELECTION EXTERNAL SIGNAL IS CHANGES INTO THE NORMAL OPERATION MODE, THE SCAN CONTROL CIRCUIT MAINTAINS **८805** THE CURRENT STATE OF THE SCAN SELECTION INTERNAL SIGNAL, WHEREBY THE n PIECES OF SCAN STORAGE ELEMENTS REMAIN IN THE SCAN MODE.

THE SCAN CONTROL CIRCUIT CHANGES THE SCAN CLOCK OF THE n PIECES OF 7806 SCAN STORAGE ELEMENTS INTO THE NORMAL OPERATION CLOCK, AND MASKS THE NORMAL OPERATION CLOCK SO THAT THE CLOCK IS NOT INPUT TO THE n PIECES OF SCAN STORAGE ELEMENTS

THE n PIECES OF SCAN STORAGE ELEMENTS HOLD AND OUTPUT THE SCAN-IN DATA RECEIVED FROM THE EXTERNAL INPUT TERMINAL, IN SYNCHRONIZATION WITH THE NORMAL OPERATION CLOCK.

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THE SCAN CONTROL CIRCUIT CHANGES THE n PIECES OF SCAN STORAGE ELEMENTS INTO THE NORMAL OPERATION MODE BY THE SCAN SELECTION INTERNAL SIGNAL.

THE n PIECES OF SCAN STORAGE ELEMENTS HOLD AND OUTPUT THE NORMAL OPERATION DATA IN SYNCHRONIZATION WITH THE NORMAL OPERATION CLOCK.

THE SCAN CONTROL CIRCUIT CHANGES THE n PIECES OF SCAN STORAGE ELEMENTS INTO THE SCAN MODE BY THE SCAN SELECTION INTERNAL SIGNAL. FURTHER, IT CHANGES THE SCAN CLOCK TO THE TEST CLOCK.

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ANOTHER NO SCAN-IN DATA SHOULD BE INPUTTED?

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THE DATA STORED IN ALL OF THE n PIECES OF SCAN STORAGE ELEMENTS ARE OUTPUT TO THE EXTERNAL OUTPUT TERMINAL IN SYNCHRONIZATION WITH THE TEST CLOCK.

END